



# RMS Emittance Measurements Using Optical Transition Radiation Interferometry at the Jefferson Lab FEL

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# Overview

- To apply Optical Transition Radiation Interferometry (OTRI) techniques to high current accelerators
- Investigate the ability of OTRI to measure complex beam distributions
- Further develop an all optical method of phase space mapping

*First step: RMS emittance measurements*





# OTRI as an Emittance Diagnostic

*Measure RMS beam size and RMS divergence at a waist condition to calculate the emittance*

RMS emittance

$$\tilde{\mathcal{E}}_x = \left( \langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2 \right)^{\frac{1}{2}}$$

*At a beam waist*

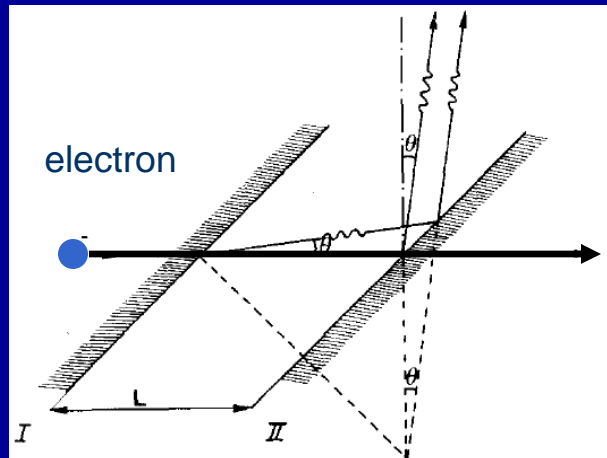
$$\tilde{\mathcal{E}}_x = x_{rms} x'_{rms}$$

where:  $x_{rms} = \sqrt{\langle x^2 \rangle}$ , and  $x'_{rms} = \sqrt{\langle x'^2 \rangle}$



# OTRI Basics

Two thin parallel metal foils



Spectral-angular distribution of two foil OTR

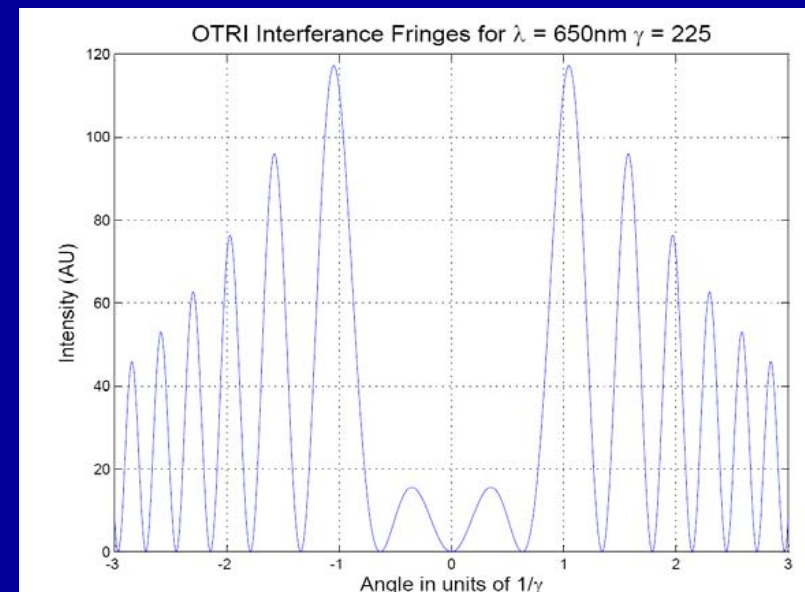
$$\frac{dI_{tot}}{d\omega d\theta} = \frac{\alpha}{\pi} \frac{\theta^2}{(\gamma^{-2} + \theta^2)^2} |1 - e^{-i\phi}|^2$$

phase term

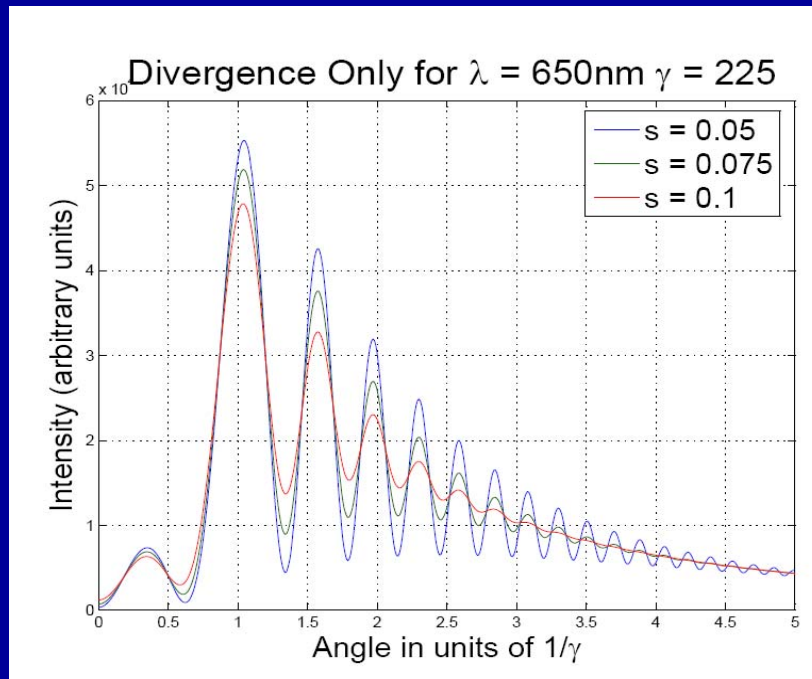
$$\phi = \frac{L}{L_v}$$

Vacuum coherence length

$$L_v = \left( \frac{\lambda}{\pi} \right) \left( \frac{1}{\gamma^{-2} + \theta^2} \right)$$



# Effect of Beam Parameters on Fringe Visibility



Interference fringes are highly sensitive to:

1. Optical bandwidth
2. Energy spread
3. **Divergence**

*We want divergence to dominate the fringe visibility effects*

*Gaussian angular distribution function*

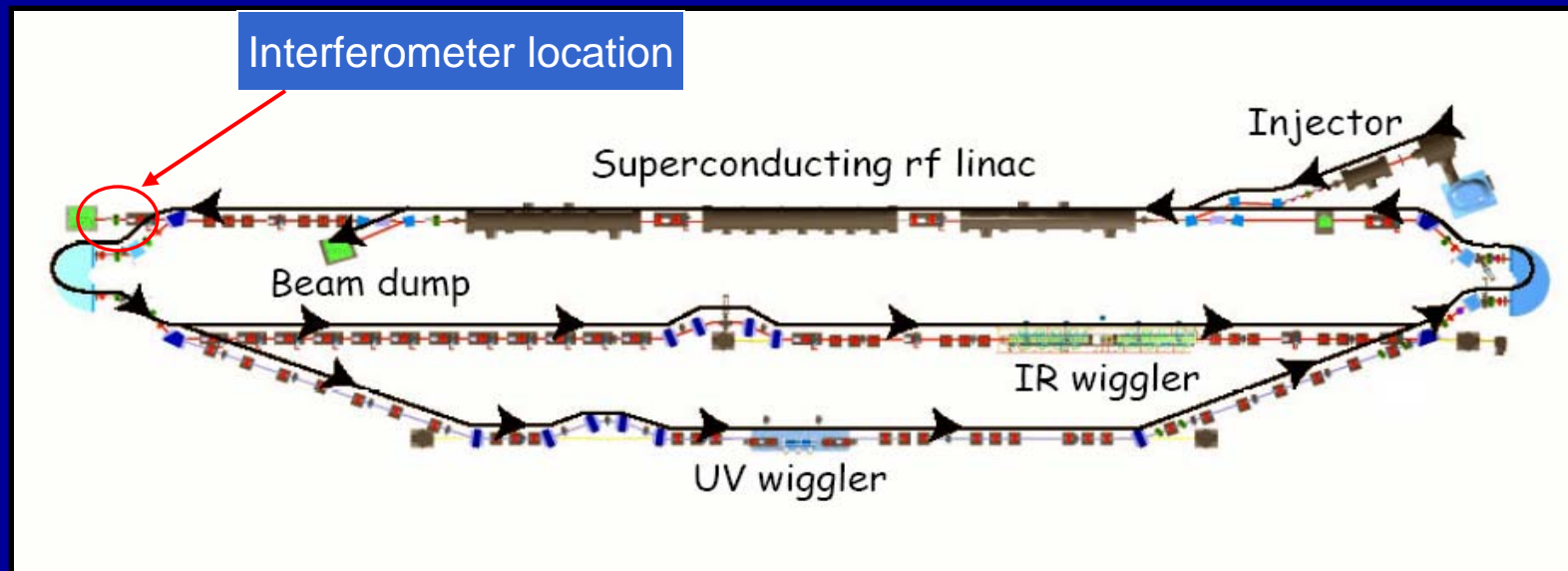
$$P(\sigma, \theta) = \left( \frac{1}{2\sigma^2} \right)^{\frac{1}{2}} e^{-\frac{\theta^2}{2\sigma^2}}$$

*Normalized divergence*

$$s = \gamma\sigma$$

- Narrow bandwidth filter makes bandwidth effects negligible
- Energy spread tolerance determined through simulation

# Experimental Setup

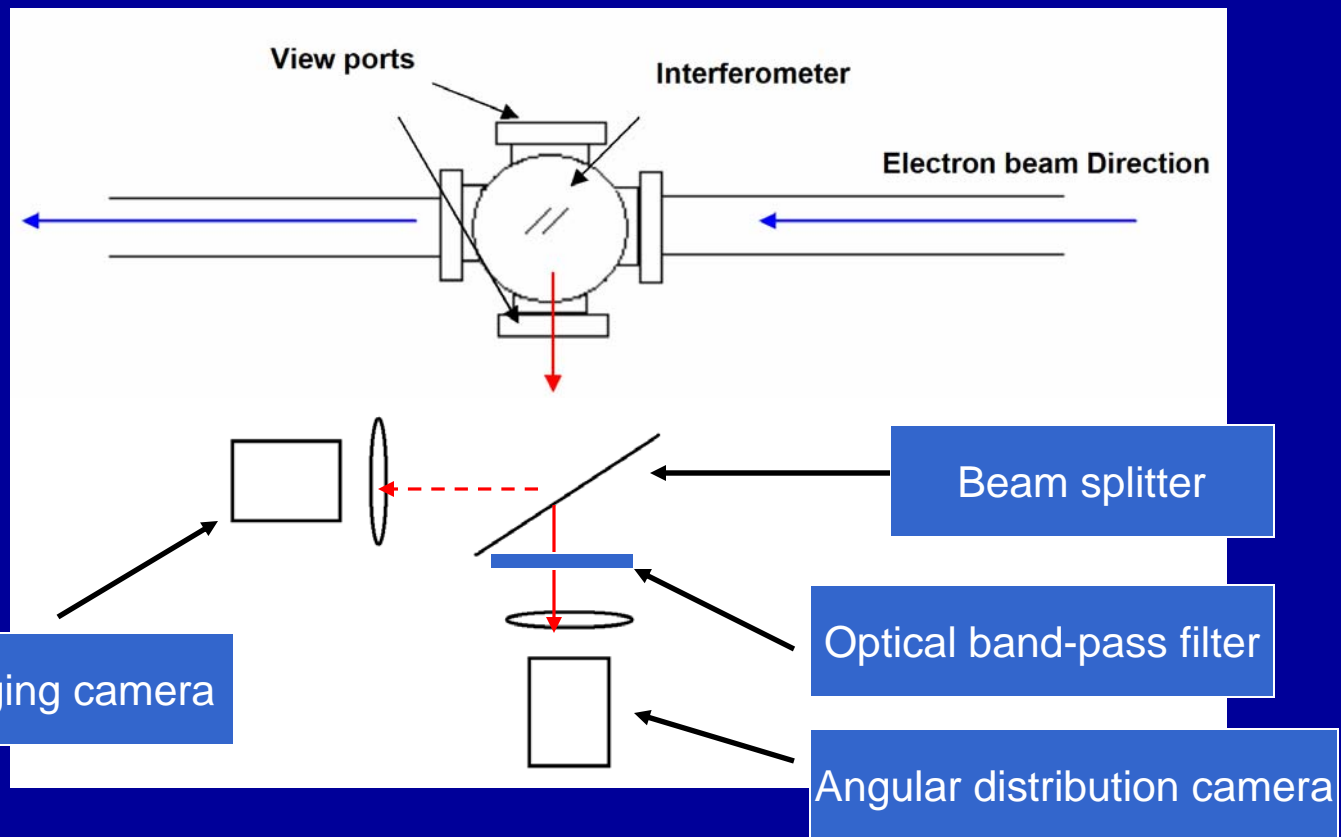


## Experimental beam conditions

Image obtained from [www.jlab.org](http://www.jlab.org)

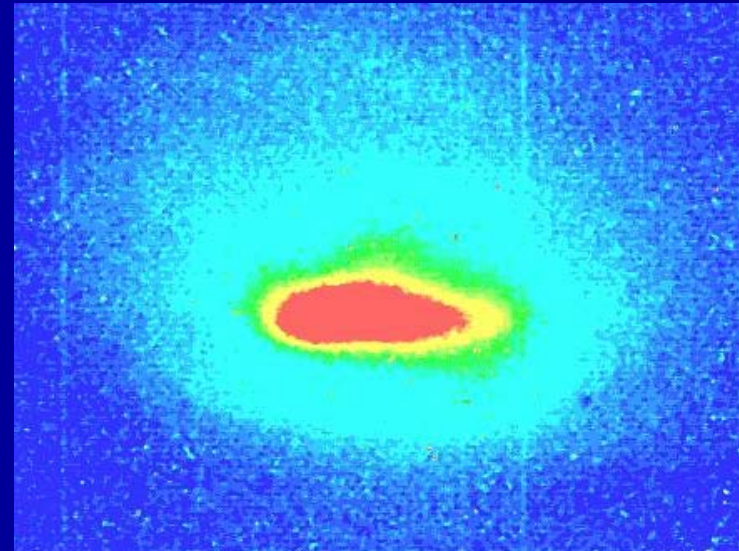
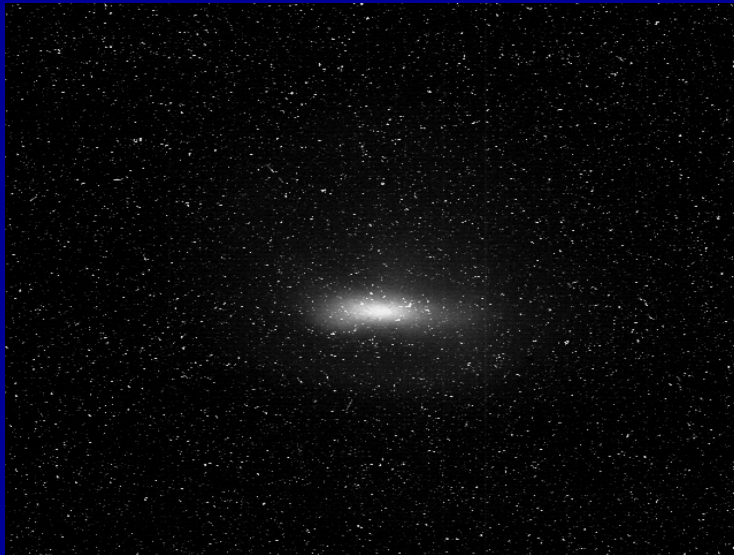
Beam Energy	115 MeV
Macro Pulse Width	100 $\mu$ s
Micro Pulse rep rate	2MHz
Charge per bunch	135 pC
Beam Current (Avg)	$\sim$ 150 $\mu$ A

# Optical Arrangement



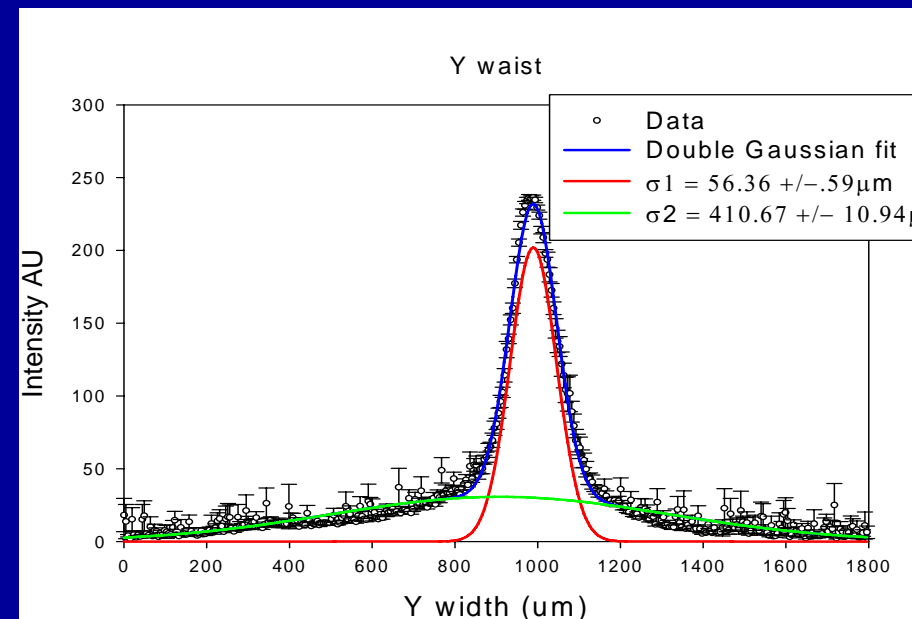
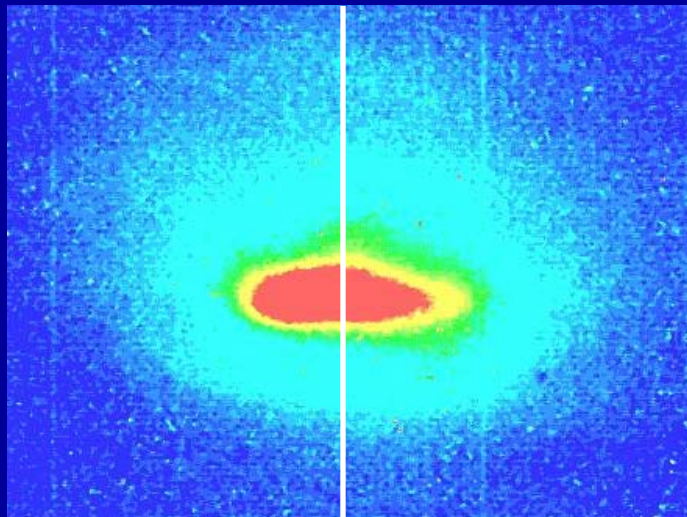
# Beam Size Measurements

*Beam image profile is complex*



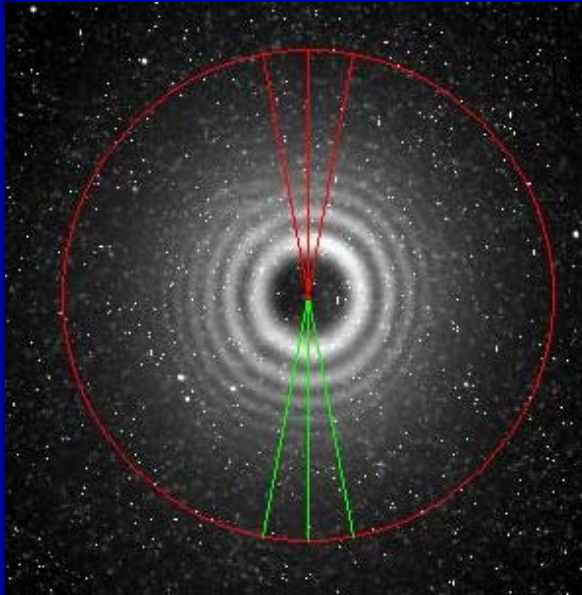


# Beam Size Measurement



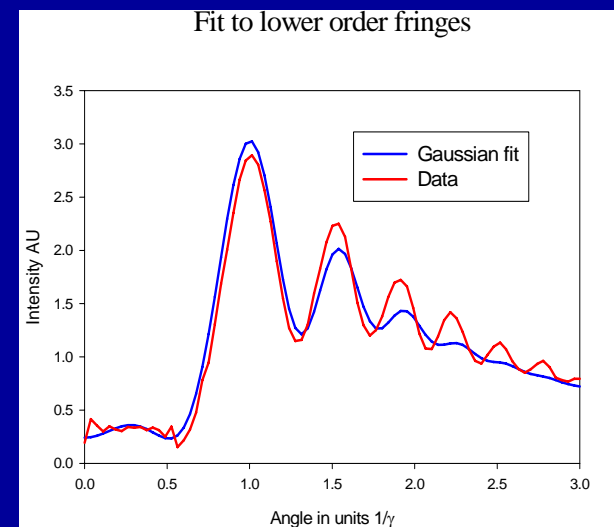
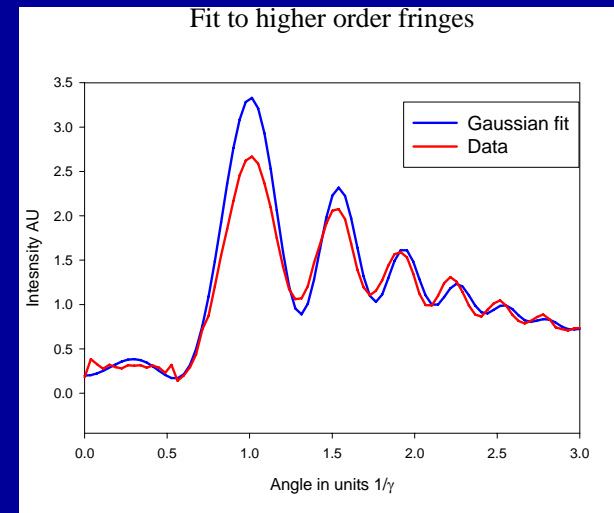
Waist	filter	$\sigma_1$ ( $\mu\text{m}$ )	$\sigma_2$ ( $\mu\text{m}$ )
X	650x10 nm	134.4+/-1.4	380.1+/-5.6
X	450x10 nm	144.9+/-2.6	390.7+/-16.9
Y	650x10 nm	56.4+/-0.59	410.7+/-11.0
Y	450x10 nm	49.4+/-1.0	380.5+/-14.8

# Divergence Measurements



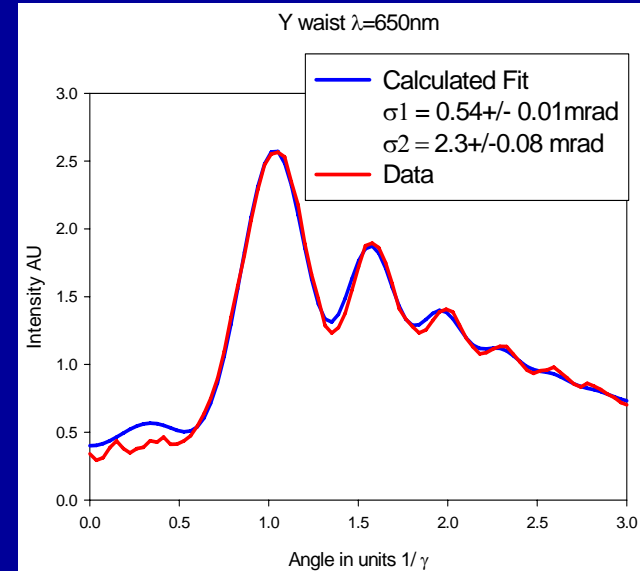
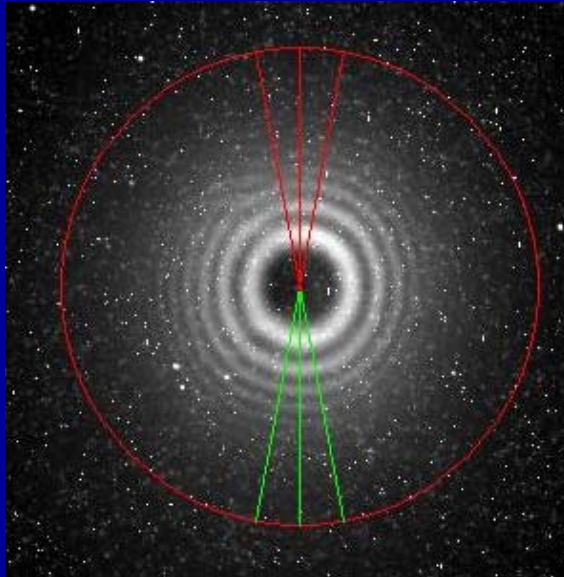
- Sector scan of far field image provides intensity profile
- Computer code used to fit intensity profile

## Simple Gaussian does not work



# Divergence Measurements

*Two Gaussian fit works remarkable well*



Waist	Filter	$\theta_1$ (mrad)	$\theta_2$ (mrad)
Y	650x10 nm	0.54 +/- .01	2.3 +/- 0.1
Y	450x10 nm	0.55 +/- 0.01	2.4 +/- 0.08
X	650x10 nm	0.43 +/- 0.01	1.4 +/- 0.08
X	450x10 nm	0.45 +/- 0.01	1.3 +/- 0.07



# Emittance Measurements

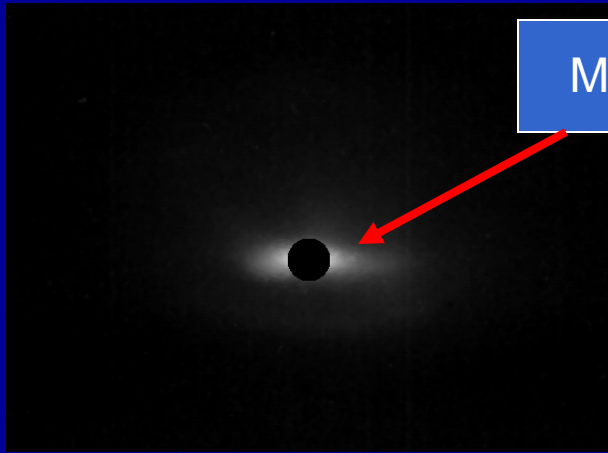
Waist	filter	Inner $\sigma$ (mm-mrad)	Outer $\sigma$ (mm-mrad)
X	650x10 nm	13 +/- .4	117.2 +/- 7.7
X	450x10 nm	14.7 +/- .7	126.5 +/- 14.0
Y	650x10 nm	6.8 +/- .2	212.5 +/- 14.9
Y	450x10 nm	6.0 +/- .2	205.4 +/- 14.9

## Conclusion

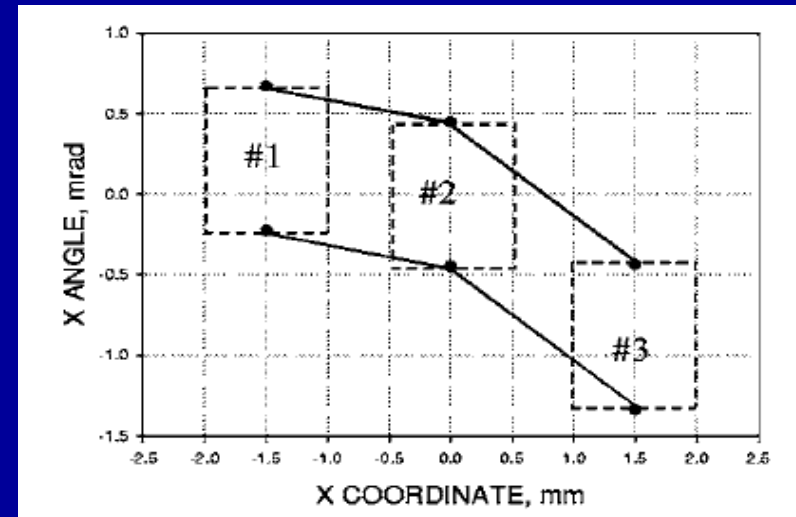
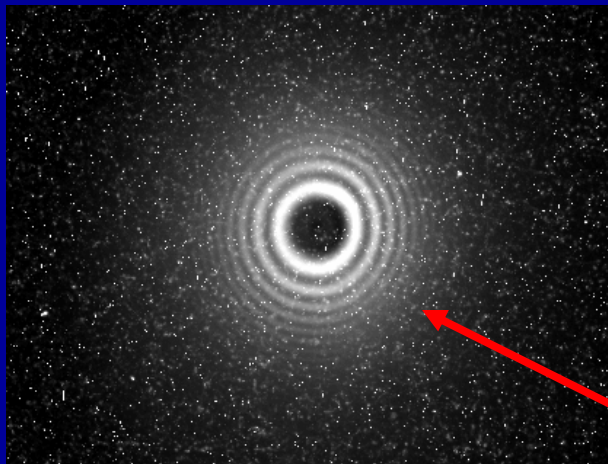
- OTRI has shown potential to measure multiple spatial and angular components within the beam
- Need to use a method to correspond spatial and angular data



# Next Step: Optical Masking and Optical Phase Space Mapping



Measure position



R.B. Fiorito, et al., Ed. G.A. Smith and T. Russo "Optical Methods for Mapping the Transverse Phase Space of a Charged Particle Beam", Beam Instrumentation Workshop Conference Proceedings, AIP Conf. Proc. no. 648, p 187, (2002).

Measure divergence and centroid shift



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